Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/681,269	LEE ET AL.	
Examiner	**Art Unit**	
Hai L. Nguyen	2816	

SEARCHED

Class	Subclass	Date	Examiner
331	16,17,34, 175,177, 184	4/2/2005	HLN
330	258		
327	536,537		
	589,148		
	157,390		

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)

	DATE	EXMR
Consulted with Minh Nguyen, Primary Examiner, AU #2816	3/31/2005	HLN
Shepardize Search	4/3/2005	HLN